

<b>Notice of References Cited</b>	Application/Control No. 10/538,202		Applicant(s)/Patent Under Reexamination CHANG, CHIN	
	Examiner Amara Abdi		Art Unit 2624	Page 1 of 1

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*	B	US-2003/0076056	04-2003	Schuurmans, Frank Jeroen Pieter	315/291
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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